

<b>Notice of References Cited</b>	Application/Control No. 09/895,866	Applicant(s)/Patent Under Reexamination SAMBASIVAN ET AL.	
	Examiner Colleen P Cooke	Art Unit 1725	Page 1 of 1

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	C	US-6,537,689	03-2003	Schoop et al.	428/701
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Kumar et al., "Enhancement in critical current density of Y1Ba2Cu3O(7-beta) thin films on hastelloy with TiN buffer layers" Applied Physics Letters, August 24, 1992, Volume 61, Issue 8, pp. 976-978.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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